



**PATENT**

Attorney Docket No.: 16869P-041800US

Client Ref. No.: 210100244US1

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re application of:

AKIRA HAMAMATSU *et al.*

Application No.: 10/082,593

Filed: February 22, 2002

For: SEMICONDUCTOR DEVICE  
INSPECTION METHOD

Customer No.: 20350

Confirmation No.: 5740

Examiner: Hoa B. Trinh

Technology Center/Art Unit: 2814

**AMENDMENT UNDER 37 CFR 1.116  
EXPEDITED PROCEDURE  
EXAMINING GROUP 2814**

**Mail Stop AF**

Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

Sir:

In response to the Final Office Action mailed June 24, 2005 on the above-referenced application, please enter the following amendments and remarks:

**Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.

**Remarks/Arguments** begin on page 5 of this paper.